

Measurements and Standards to Characterize Nano-Enabled Applications of Electronics: Perspectives from IEC

2011 International Conference on Frontiers of Characterization and Metrology for Nanoelectronics

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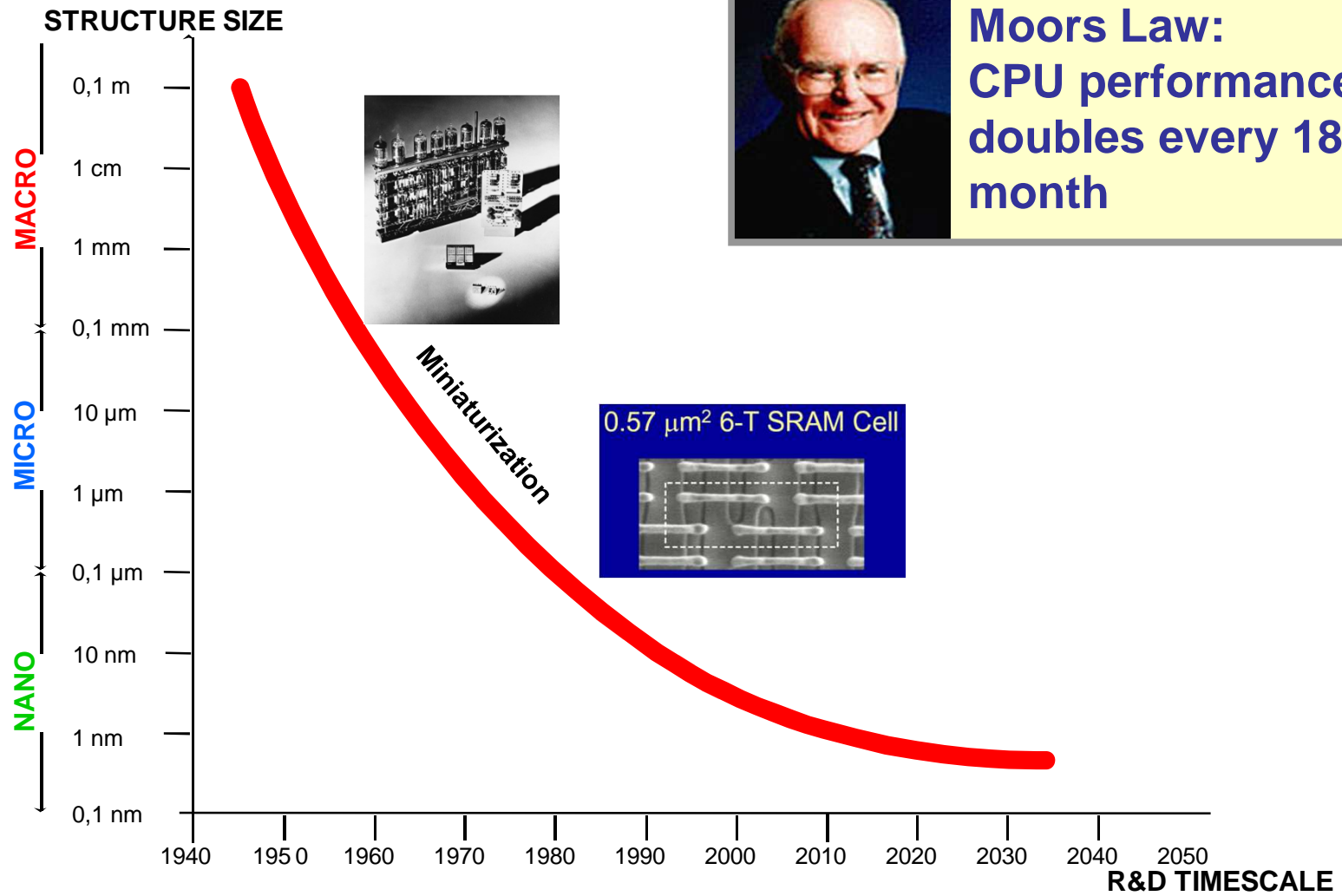
Secretary IEC/TC 113
Secretary CLC/SR 113
Obmann DKE/K 141

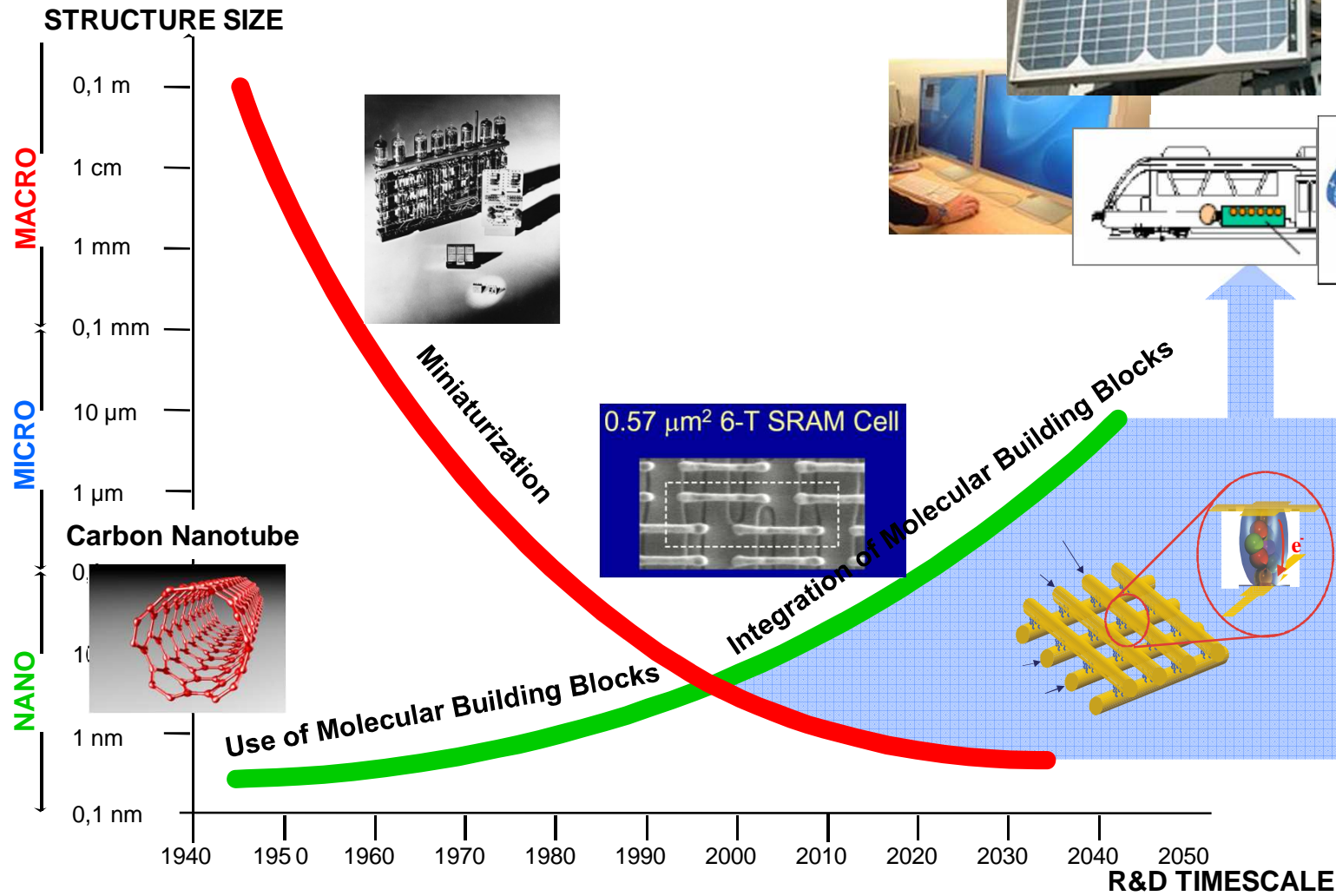
IEC/TC 113: NANOTECHNOLOGY STANDARDIZATION FOR
ELECTRICAL AND ELECTRONIC PRODUCTS AND SYSTEMS

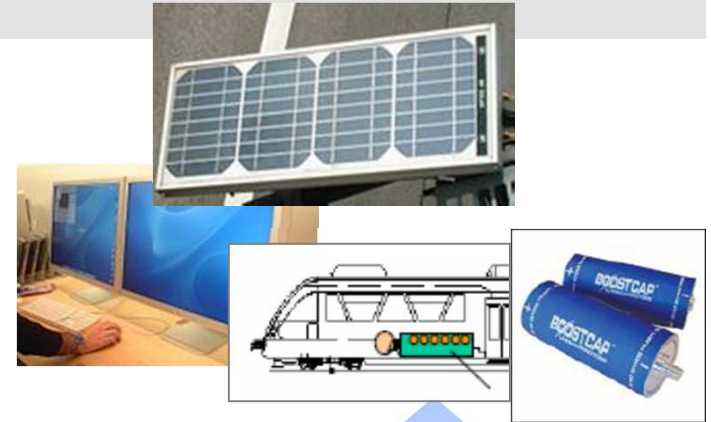
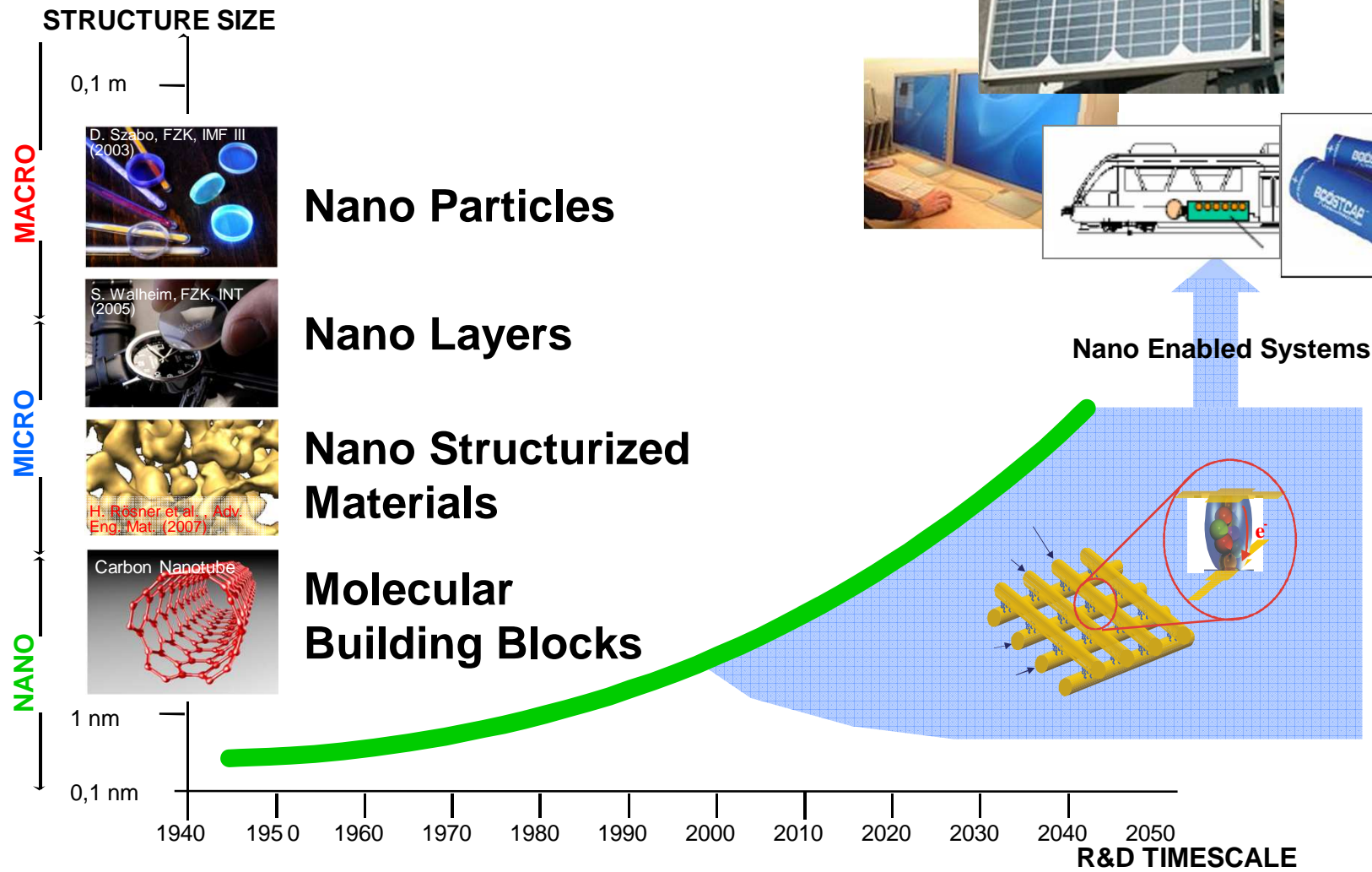


Outline

- **More than Moore versus nano-enabled**
- **IEC technical committee on nano-electrotechnologies**
- **Framework of standards for nanofabrication**
 - **Key control characteristics**
 - **Blank detail specifications**
- **Programme of work of IEC/TC 113**
- **Active participation in the standardization process**

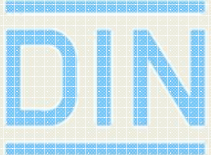






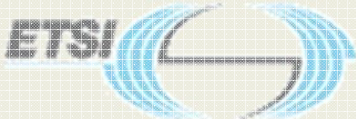







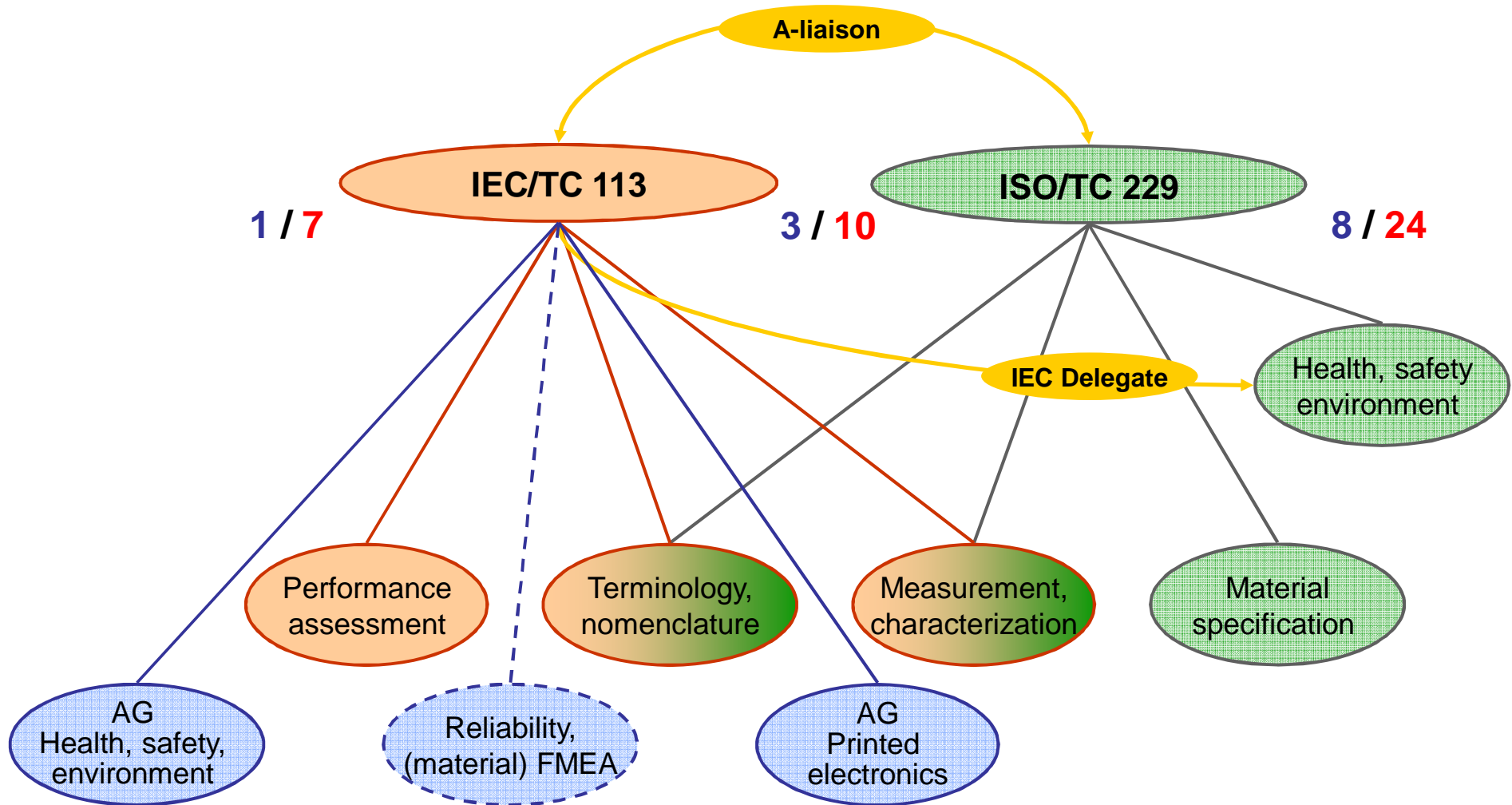


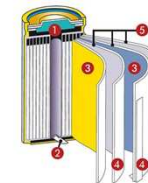
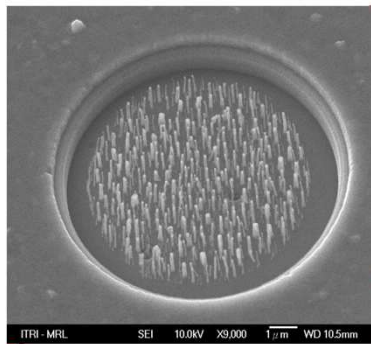
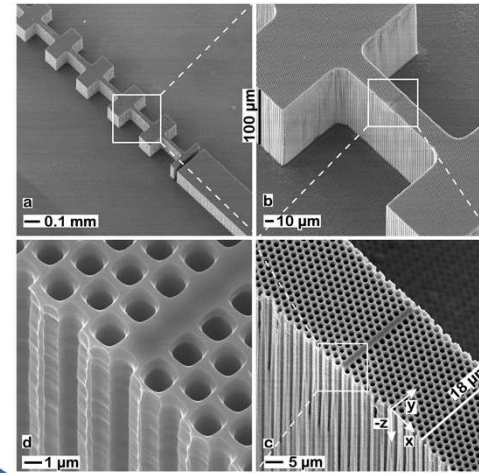
National and International Nanotechnology Standardization

	National e.g. Germany	Regional e.g. Europe	International
General	 NA 062-08-17 AA	 TC 352 (UK)	 TC 229 (UK)
Electro- technology	 K 141	 SR 113 (DE)	 TC 113 (DE)
Tele- communication	 VDE DIN		



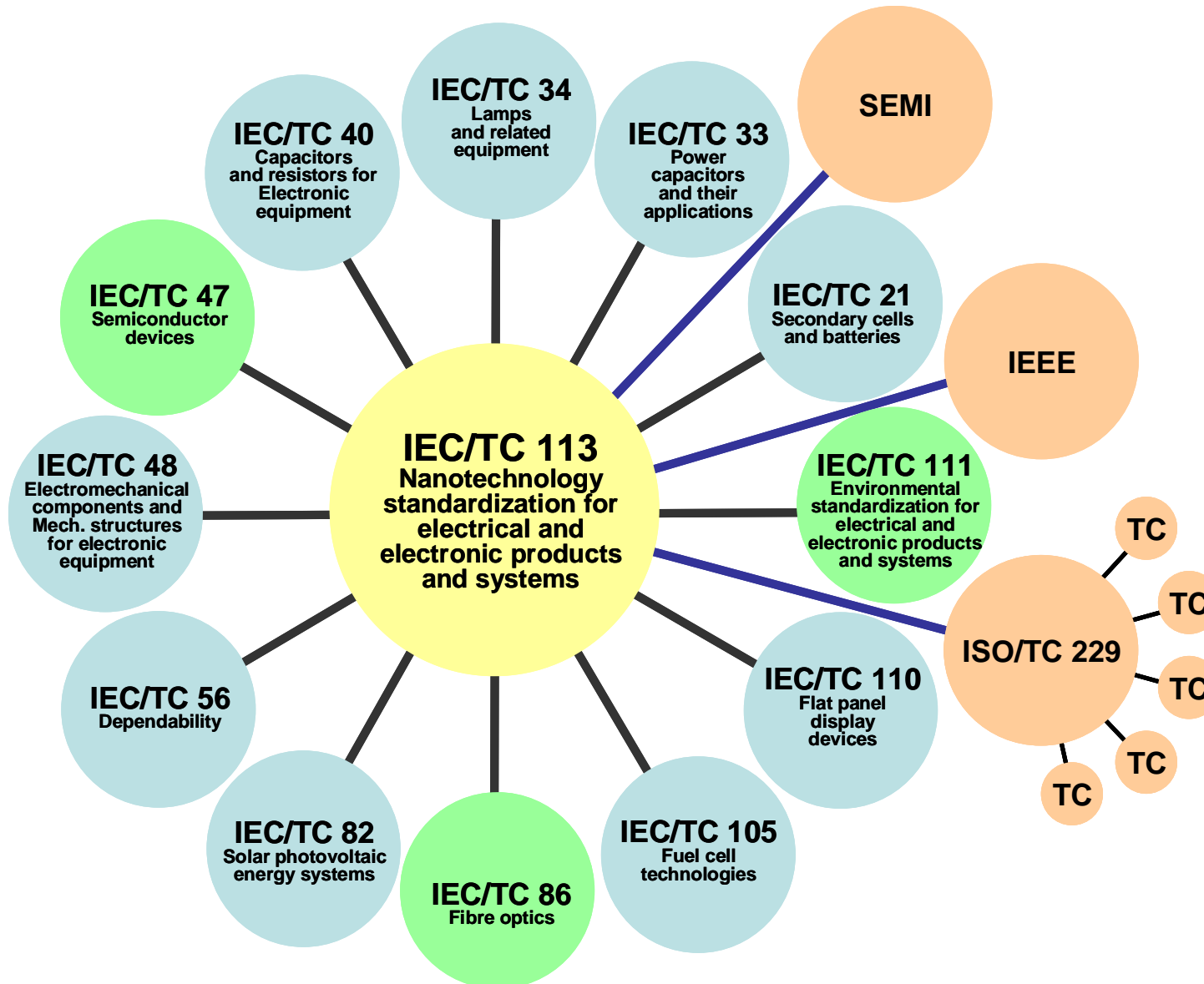
Overview nano-standardization within IEC and ISO





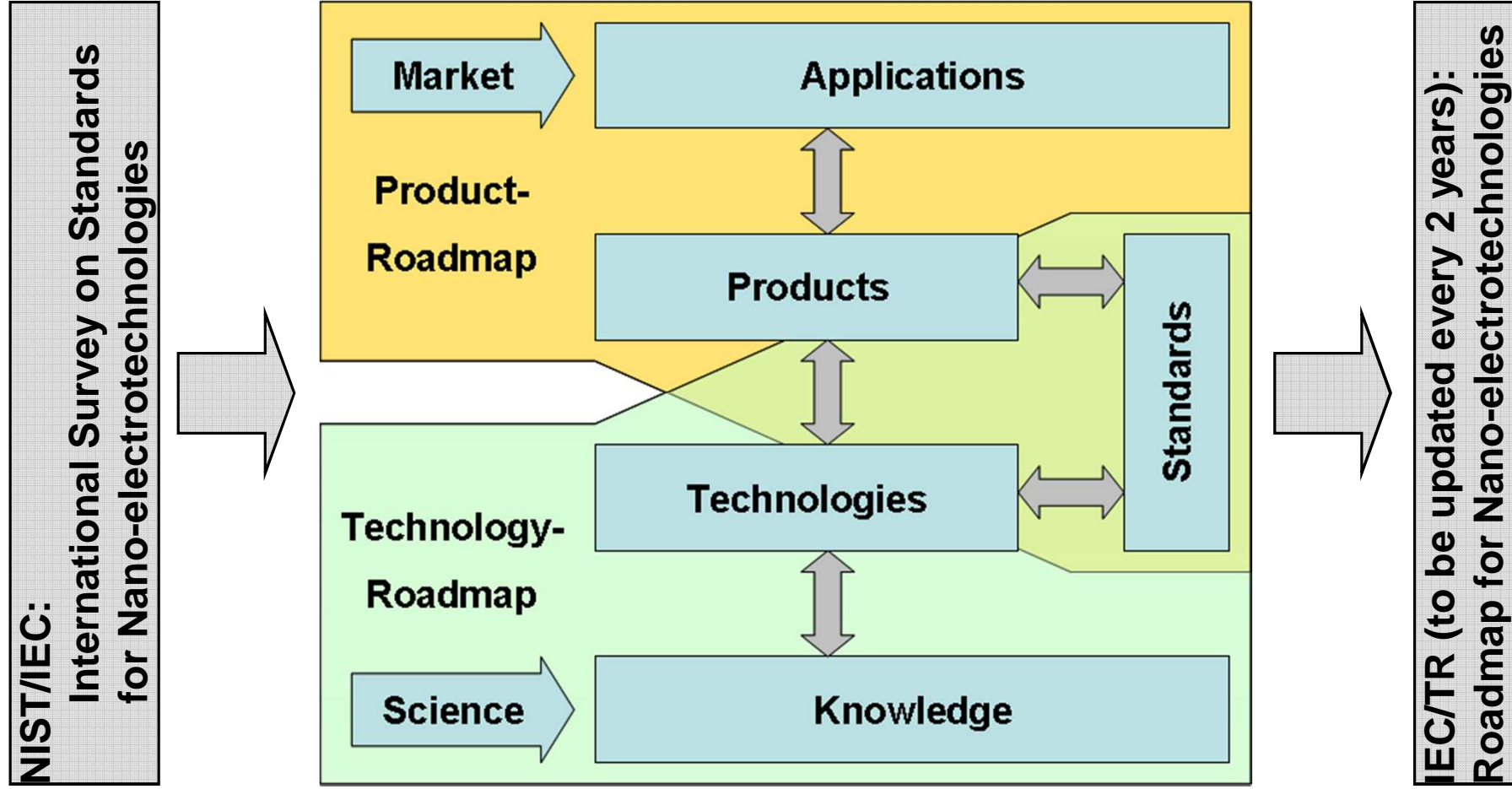


Current and potential liaisons for IEC/TC 113



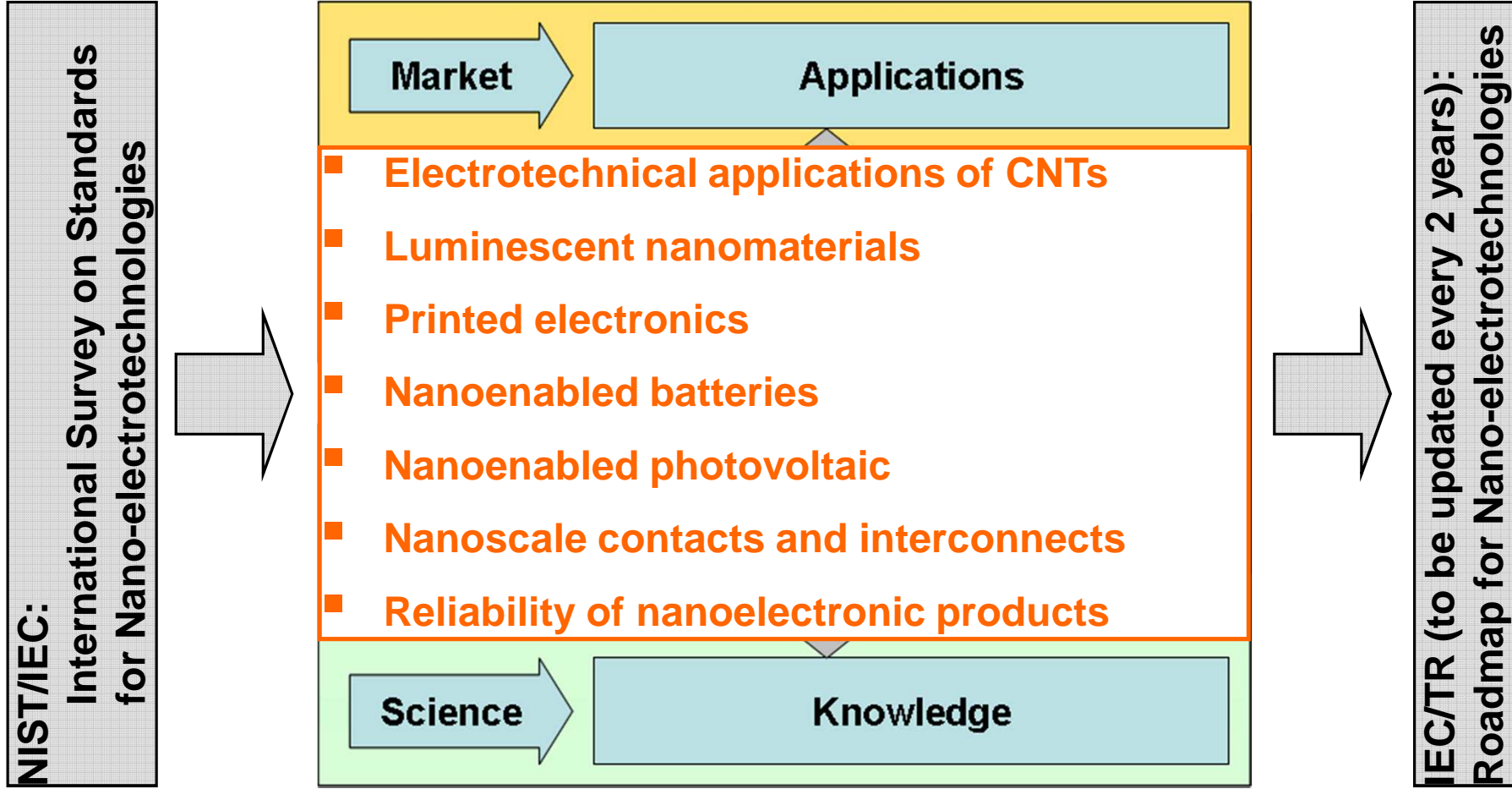


IEC Nanoelectronic Standards Roadmap





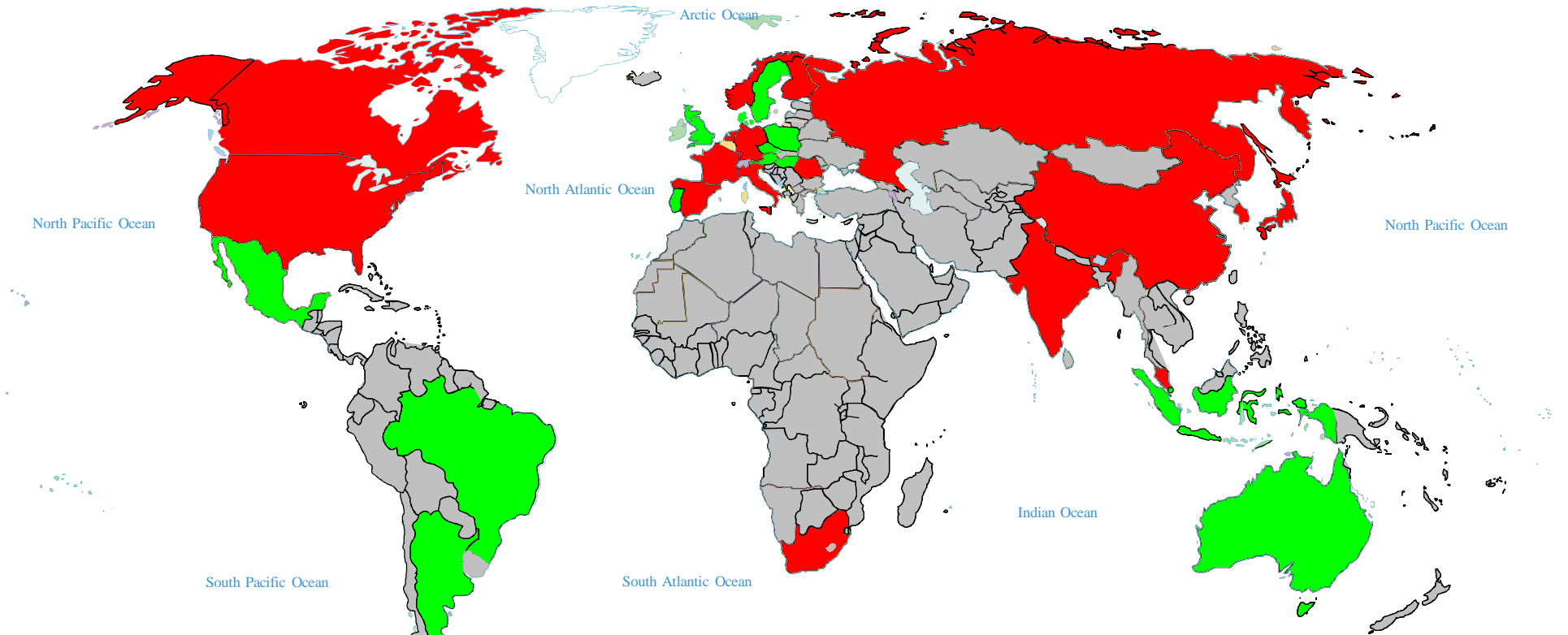
IEC Nanoelectronic Standards Roadmap






Standardization = Global Consensus Achievement

Example IEC/TC 113



Engineering



**IEEE
Nanotechnology
Council**

Equipment



Economies



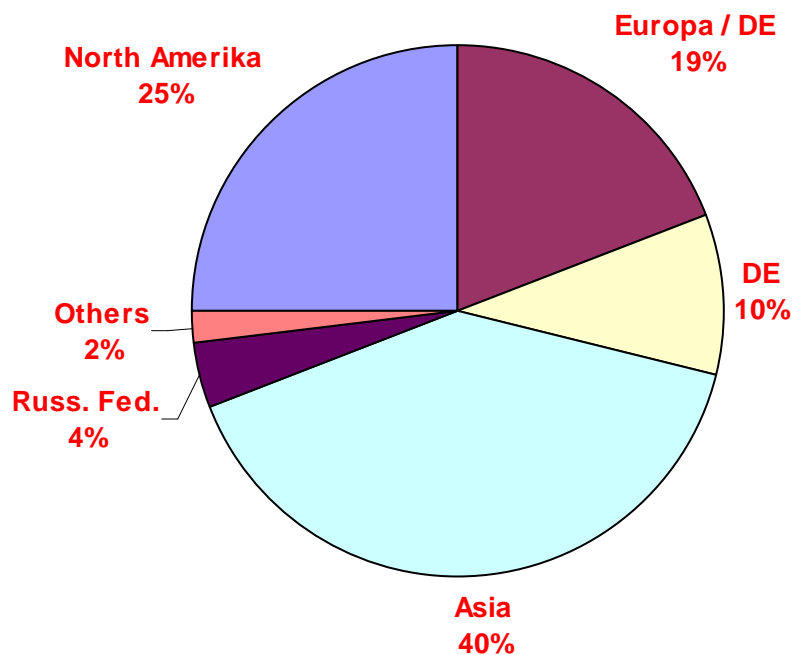
**Hongkong
Taiwan**

P-Member
O-Member

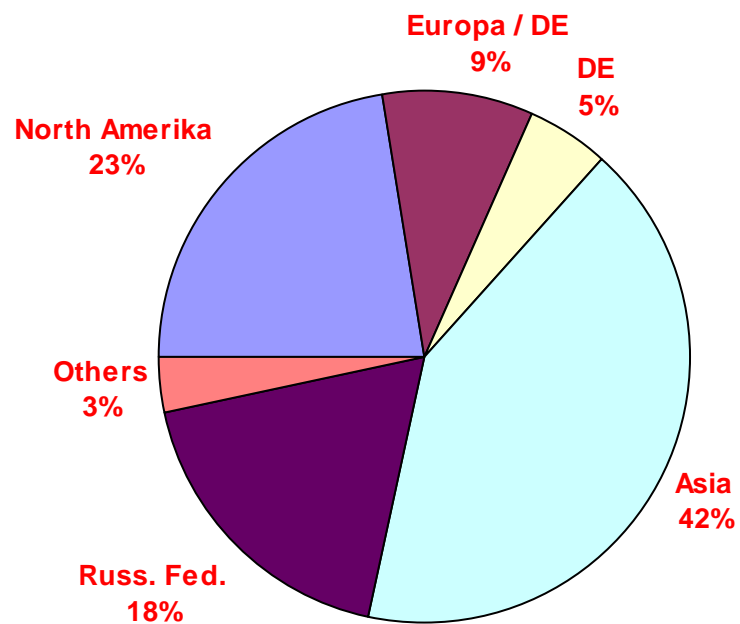


National participation in IEC/TC 113

12/2008
52 Experts

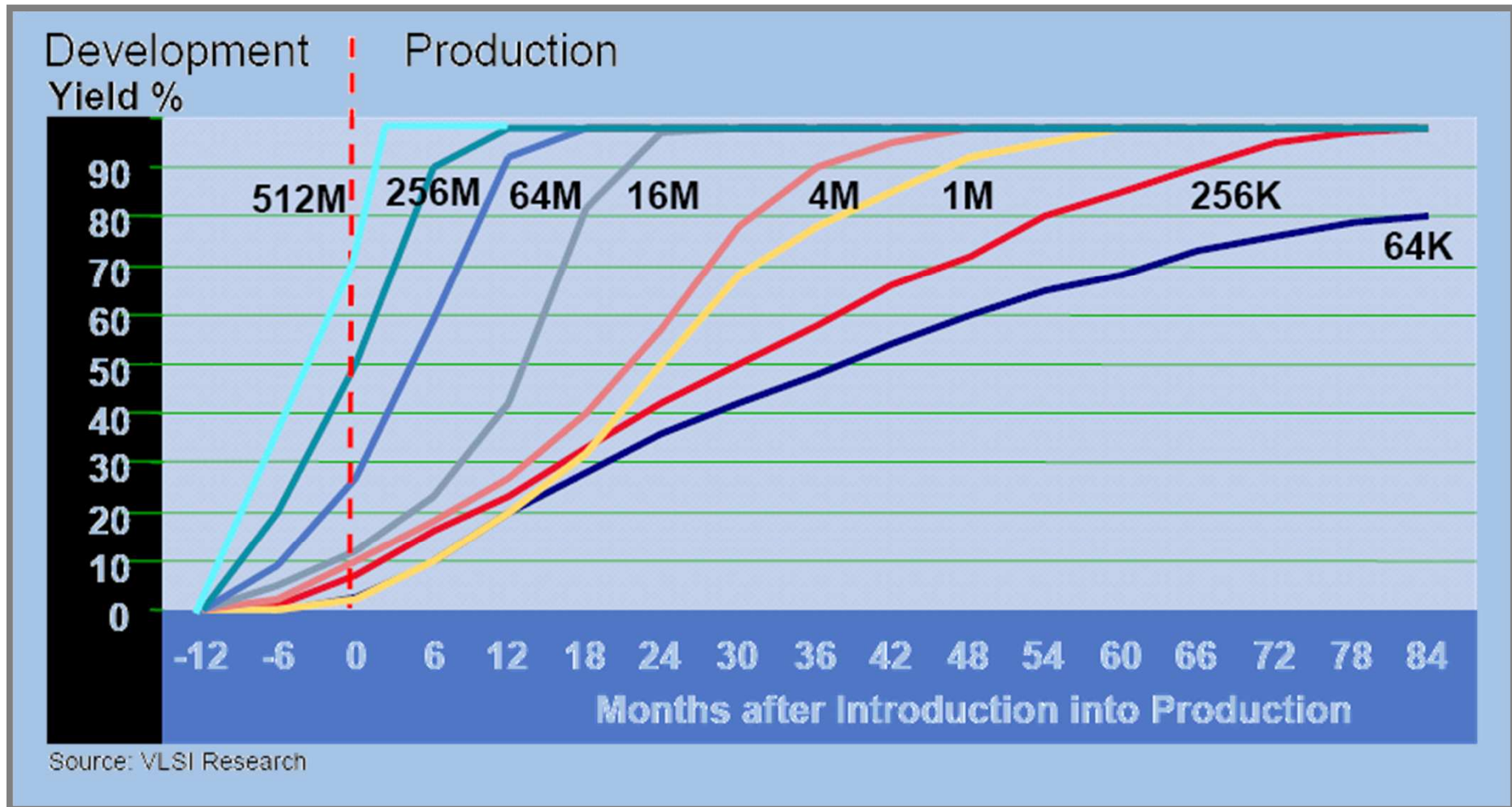


12/2010
154 Experts



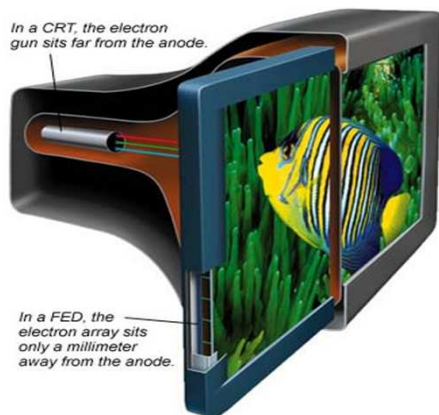


Progress by QM / Material and Process Control: Ramp up for DRAMs faster and faster





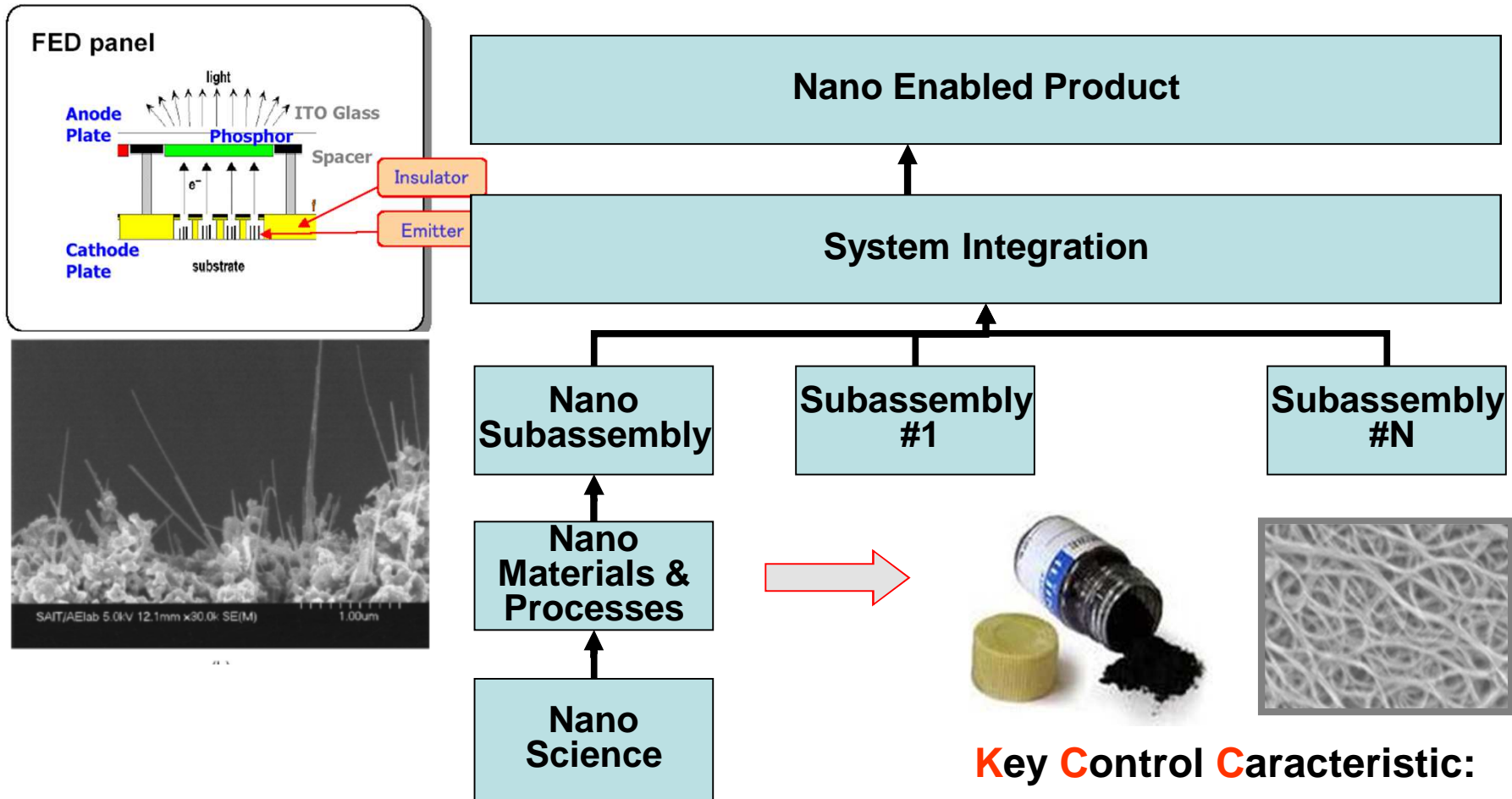
Value Adding Chain for Nano-Electronics



Nano Enabled Product

Example:

Flat Panel Displays made from CNT

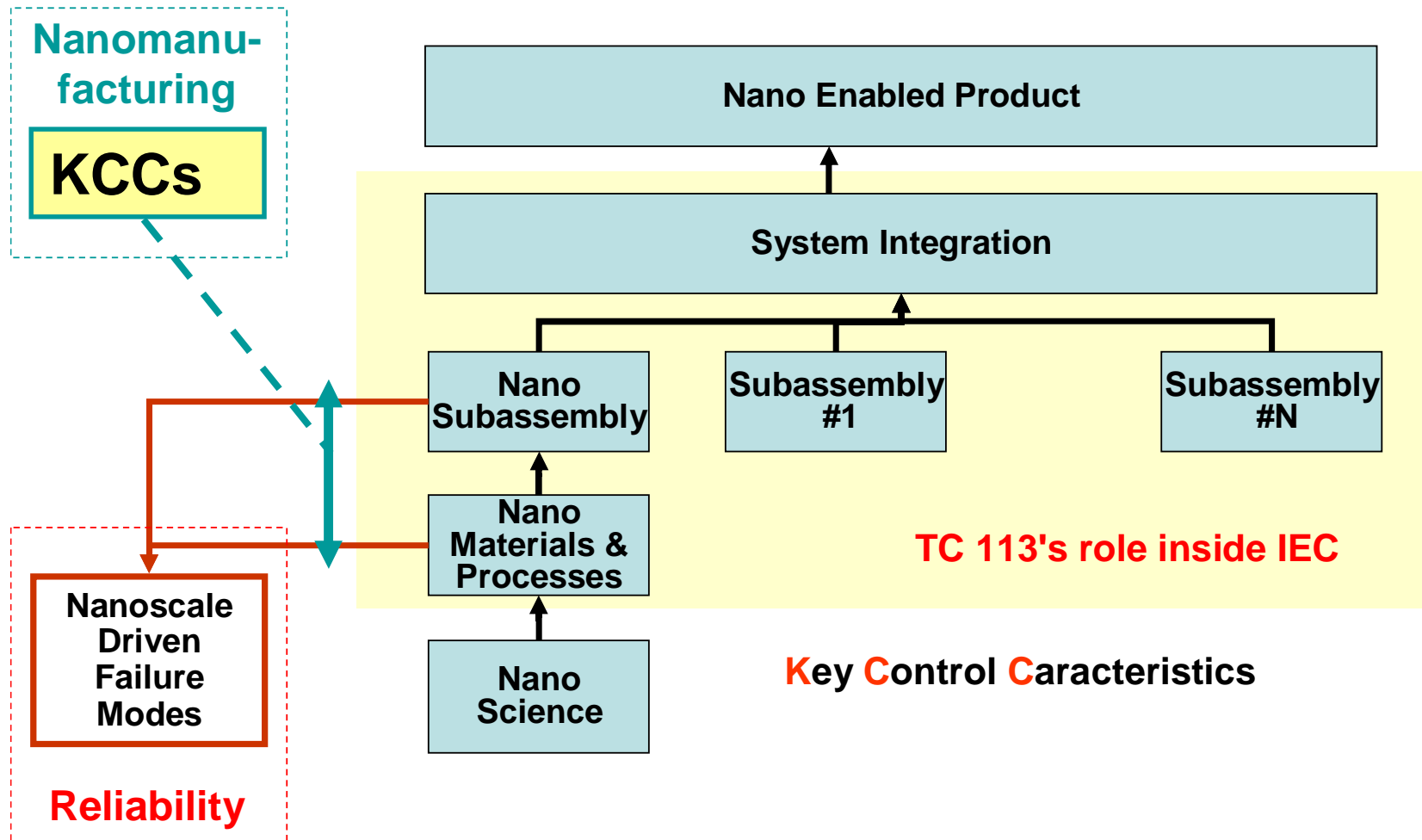


Key Control Characteristic:

An electrical property describing the CNT raw material for this application

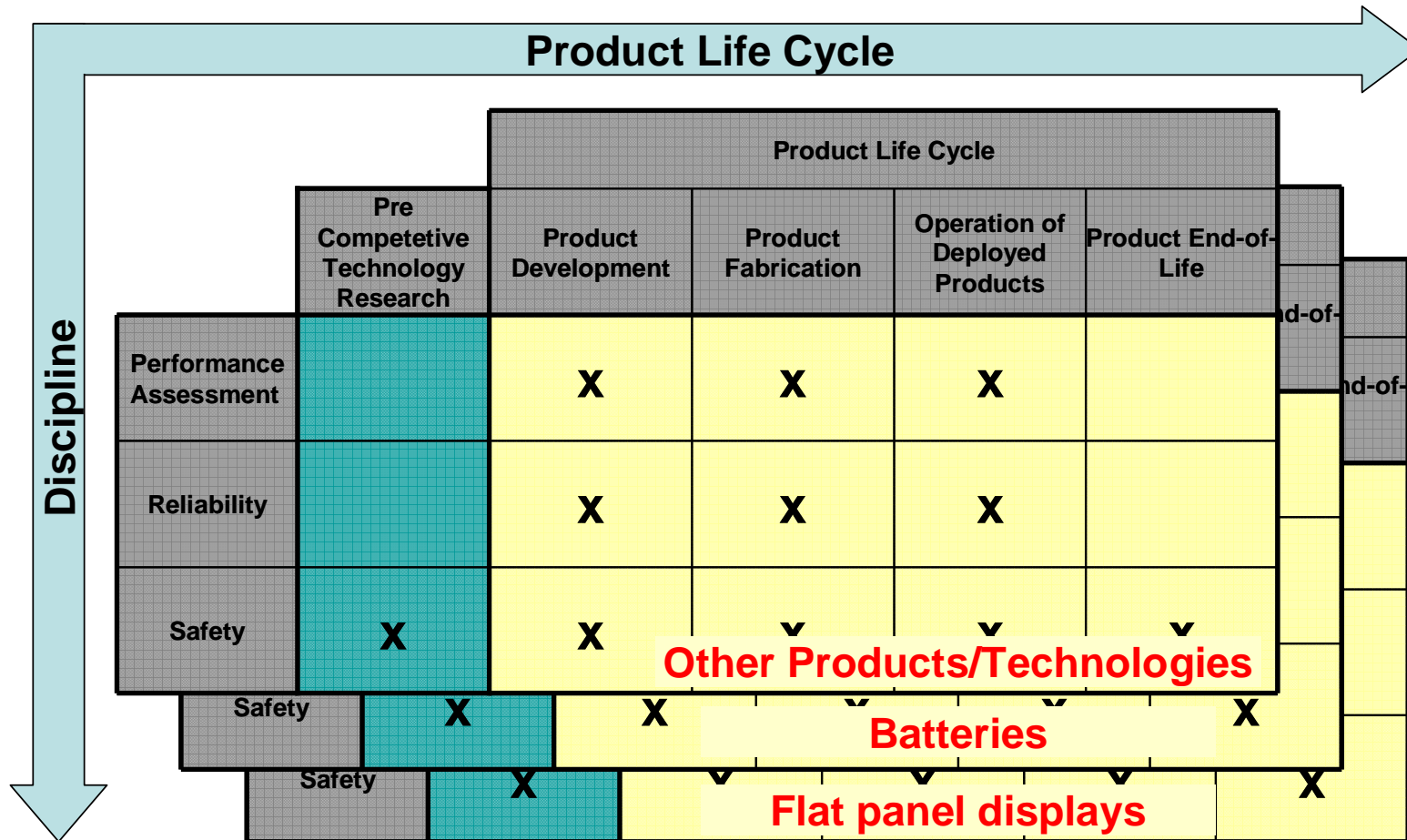


The Value Adding Chain



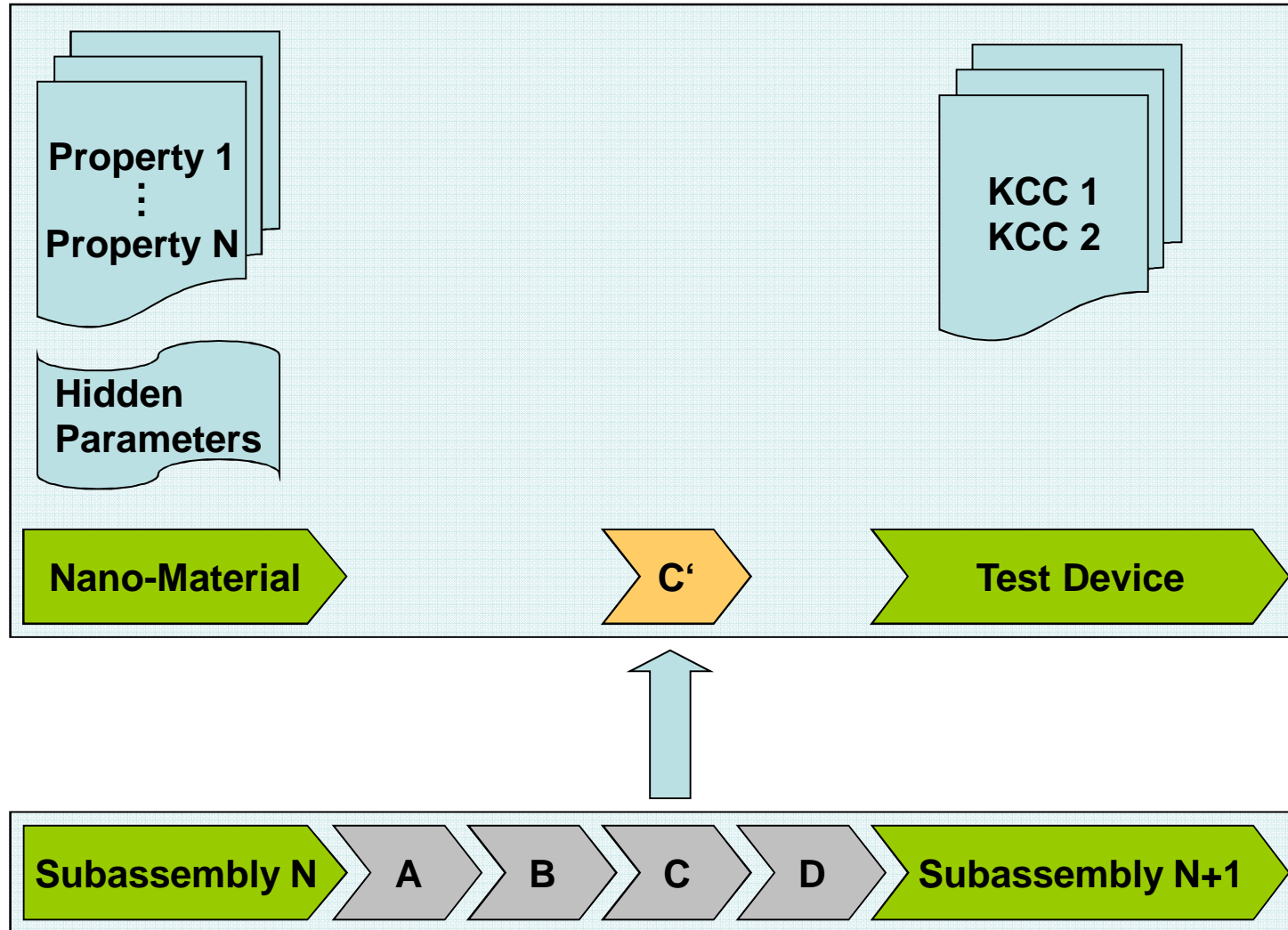


Standardization for the whole Product Life Cycle

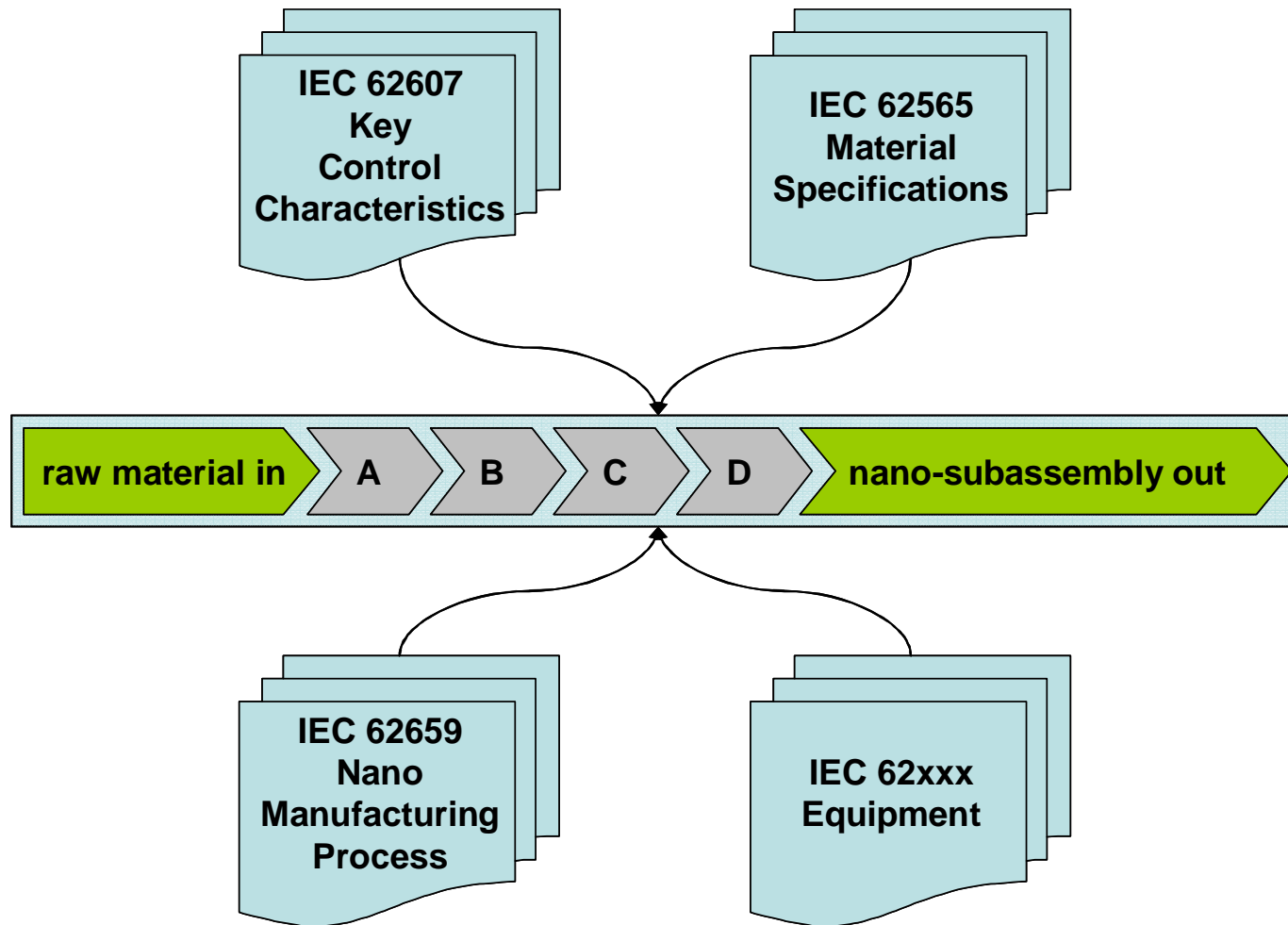


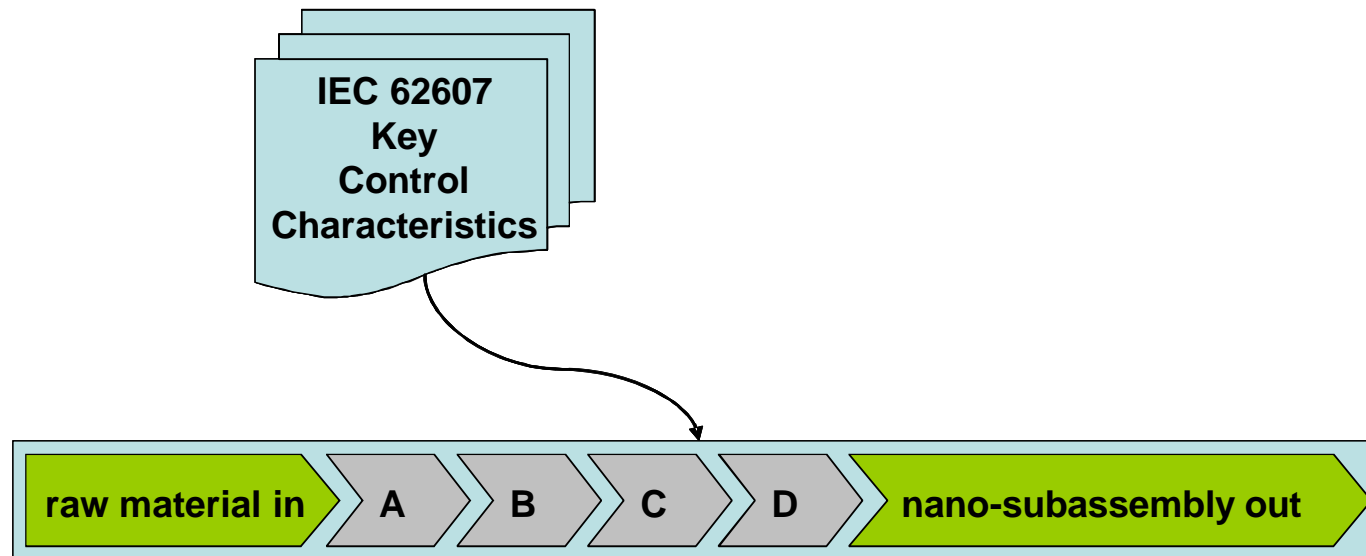


Material Specifications and Key Control Characteristics



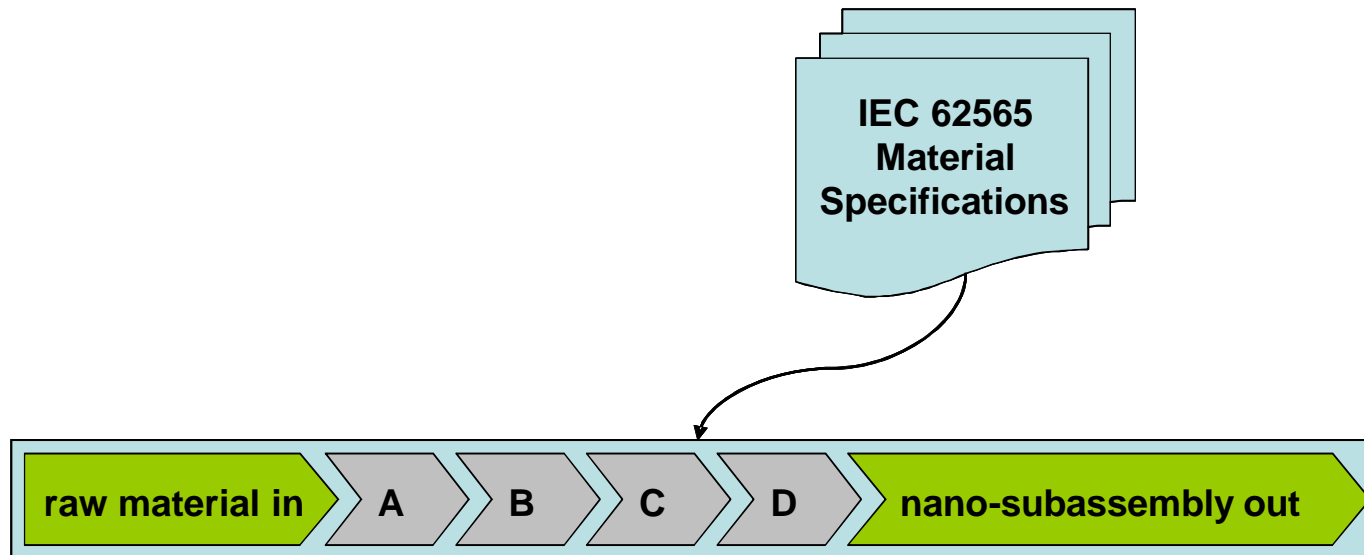
Process C' = Control Process C





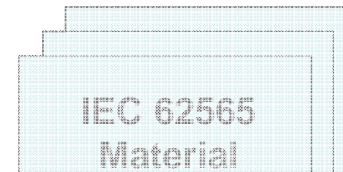
IEC 62607: Nanomanufacturing – Key control characteristics

- Part 2-1: Carbon nanotube materials - Film resistance
- Part 3-1: Luminescent nanoparticles - Quantum efficiency



IEC 62565: Nanomanufacturing - Material specifications

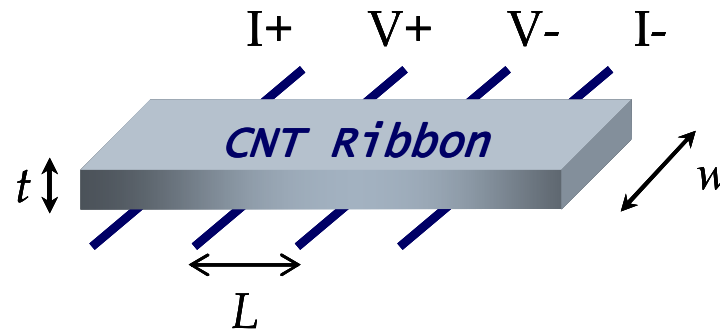
- Part 1: Basic concept
- Part 2-1: Single-wall carbon nanotubes - Blank detail specification



IEC 62565: Nanomanufacturing - Material specifications

- **Part 1: Basic concept**
- **Part 2-1: Single-wall carbon nanotubes - Blank detail specification**
- **Part 3-1: Multiwall carbon nanotubes - Blank detail specification**
- **Part 4-1: Graphene - Blank detail specification**
- **Part 5-1: Quantum dots- Blank detail specification**
- **Part 6-1: Nano-inks for printed electronics - Blank detail specification**

- **IEC 62607-2-1: Nanomanufacturing – Key control characteristics Part 2-1 Carbon nanotube materials - Film resistance**

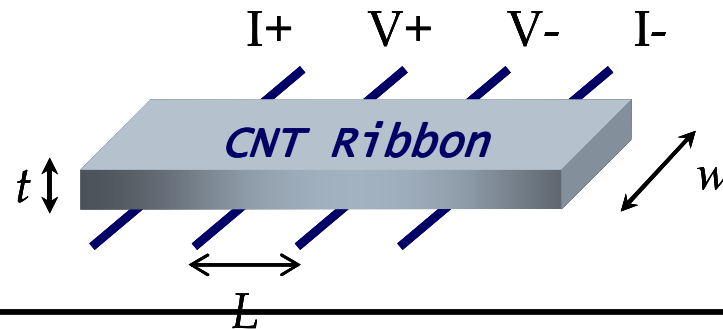


- **Method to prepare a "ribbon" made from Carbon Nano Tubes and perform measurement and report results:**
 - Description of the properties measured by the method
 - Recommendation for sample preparation
 - Outline of the experimental procedures
 - Interpretation on results and discussions on data analysis
 - Case studies



Key Control Characteristics: IEC/TS 62607

- IEC 62607-2-1: Nanomanufacturing – Key control characteristics
Part 2-1 Carbon nanotube materials - Film resistance

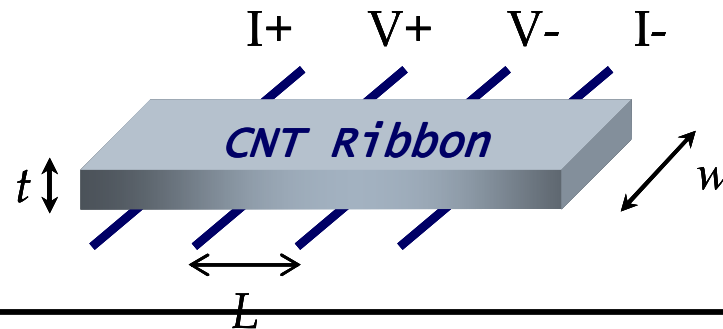


CNT	Units	1	2	3	4	5	Av
MWNT (A)	R (Ω)	19.03	27.27	27.04	20.83	20.38	
	ρ_s ($\Omega/\text{sq.}$)	5.45	5.45	5.41	5.42	5.43	5.43\pm0.02
MWNT (B)	R (Ω)	2080	1920	1860	1680	1310	
	ρ_s ($\Omega/\text{sq.}$)	693.3	672.0	620.0	616.0	679.5	656.17\pm35.7
MWNT (C)	R (Ω)	226.8	185.6	210.3	225.4	202.6	
	ρ_s ($\Omega/\text{sq.}$)	83.92	89.09	92.53	78.89	83.07	85.50\pm5.35
SWNT (D)	R (Ω)	9.55	7	7.4	7.6	6.4	
	ρ_s ($\Omega/\text{sq.}$)	1.43	1.40	1.53	1.52	1.79	1.53\pm0.15
SWNT (E)	R (Ω)	38.9	36.0	52.1	38.2	36.1	
	ρ_s ($\Omega/\text{sq.}$)	14.00	12.60	18.24	16.43	14.44	15.1\pm2.21



Key Control Characteristics: IEC/TS 62607

- IEC 62607-2-1: Nanomanufacturing – Key control characteristics
Part 2-1 Carbon nanotube materials - Film resistance



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Risk Management for Nanotechnology



Companies need standardized, clear and easy to implement risk management processes!



Excerpt from the work programme

- **PWI/TR 62565: Nanomanufacturing - Material specifications**
 - **Part 1 - Basic concept**
 - **Part 2-1: Single-wall carbon nanotubes - Blank detail specification**
- **IEC/TS 62607-2-1: Nanomanufacturing - Key control characteristics**
 - **Part 2-1: Carbon nanotube materials - Film resistance**
 - **Part 3-1: Luminescent nanoparticles - Quantum efficiency**
- **IEC/IEEE 62659 Large scale manufacturing of nanoelectronics**
- **PWI/TR 113-70: IEC nano-electronics standards roadmap**
- **PWI/TR 113-69: Nanoscale electrical contacts**
- **PWI 113-91: Guidelines of quality assessment for surface engineered nano electrotechnical products**



**TABLE 1. IEC/TC 113 Program of work:
Published standards**

IEC or ISO Number	Title
IEC/PAS 62565-2-1	Nanomanufacturing - Material specifications - Part 2-1: Single-wall carbon nanotubes - Blank detail specification
IEC/IEEE 62624	Test methods for measurement of electrical properties of carbon nanotubes
ISO/IEC/TS 80004-1	Nanotechnologies - Vocabulary - Part 1: Core terms
ISO/IEC/TS 80004-3	Nanotechnologies - Vocabulary - Part 3: Carbon nano- objects



**TABLE 2. IEC/TC 113 Program of work:
Projects in progress, JWG 1: Terminology and nomenclature**

IEC or ISO Number	Title
ISO/IEC/TR 12802	Nanotechnologies - Model Taxonomic Framework for Use in Developing Vocabularies - Core Concepts
ISO/IEC/TR 14786	Nanotechnologies - Framework for nomenclature models for nano-objects
ISO/IEC/TS 80004-4	Nanotechnologies - Vocabulary - Part 4: Nanostructured materials
ISO/IEC/TS 80004-5	Nanotechnologies - Vocabulary - Part 5: Nano-bio interface
ISO/IEC/TS 80004-6	Nanotechnologies - Vocabulary - Part 6: Nanoscale measurement and instrumentation
ISO/IEC/TS 80004-7	Nanotechnologies - Vocabulary - Part 7: Healthcare - Diagnostics and therapeutics
ISO/IEC/TS 80004-8	Nanotechnologies - Vocabulary - Part 8: Nanomanufacturing processes
IEC/ISO/TS 80004-9	Nanotechnologies - Vocabulary - Part 9: Electrotechnical products and systems
IEC/ISO/TS 80004-10	Nanotechnologies - Vocabulary - Part 10: Photonics components and systems



**TABLE 3. IEC/TC 113 Program of work:
Projects in progress, JWG 2: Measurement and characterization**

IEC or ISO Number	Title
ISO/IEC/TS 10797	Nanotechnologies - Characterization of single-wall carbon nanotubes using transmission electron microscopy
ISO/IEC/TS 13278	Nanotechnologies - Determination of elemental impurities in samples of carbon nanotubes using inductively coupled plasma mass spectrometry
IEC/ISO/TS 62622	Nanotechnologies - Description, measurement and dimensional quality parameters of artificial gratings



**TABLE 4. IEC/TC 113 Program of work:
Projects in progress, WG 3: Performance assessment**

IEC or ISO Number	Title
PWI/TR 113-69	Nanoscale electrical contacts and interconnects
PWI/TR 113-70	IEC nanoelectronics standards roadmap
PWI 113-91	Guidelines of quality assessment for surface engineered nano-electrotechnical products
IEC/TR 62565-1	Nanomanufacturing - Material specifications - Part 1: Basic concept
IEC 62565-2-1	Nanomanufacturing - Material specifications - Part 2-1: Single-wall carbon nanotubes - Blank detail specification
IEC/TS 62607-2-1	Nanomanufacturing - Key control characteristics - Part 2-1: Carbon nanotube materials - Film resistance
IEC/TS 62607-3-1	Nanomanufacturing - Key control characteristics - Part 3-1: Luminescent nanoparticles - Quantum efficiency
IEC/IEEE 62659	Large scale manufacturing of nanoelectronics

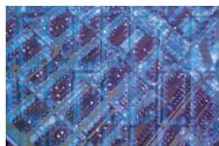


Participation on the Standardization Process

To Support:



Global Market



Innovation

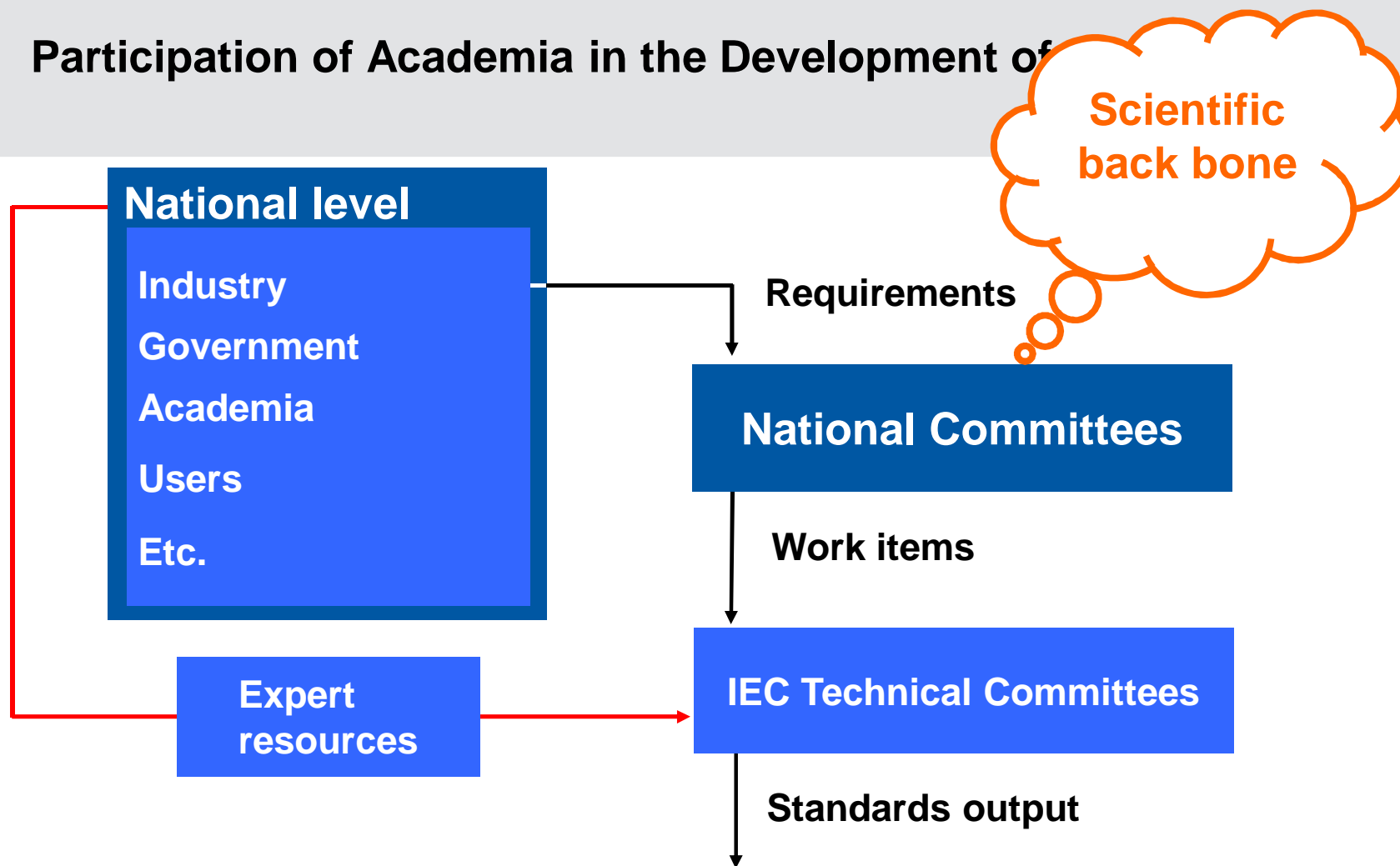


Efficiency



Regulation

- **Members of the IEC technical committees ...**
reduce international barriers for global trade. Companies which send their employees into committees knows about upcoming standards early.
- **Members of the IEC technical committees ...**
meet other technical experts and exchange up-to-date technical information. It's proven that companies which are active in standardization are typically well positioned in the market.
- **Members of the IEC technical committees ...**
helps to increase efficiency in fabrication and business processes. Companies can concentrate on product design if the daily working processes are supported by standards.
- **Members of the IEC technical committees ...**
defines the state-of-the-art in a technology and supports regulation processes. Companies active in standardization feed in their stakeholder know-how before regulation takes place.



Increase the participation of academia in the standardization process

- Mandatory evaluation of research projects regarding their impact on standardization
- Benefit of participation in standardization for the academic career
- Founding of travelling cost to international standardization meetings



Importance of Nanotechnology Standardization in the Chinese Scientific Community

The German–China Bi-lateral Forum on Frontier of Nanotechnology and Nanostandardization 2009. 9. 5





"Summary" or "is there any Benefit from Standardization" ?

